



## Press release

### Probes for Pulse Injection into IC-Die for EMI and Interference Investigations and Side Channel Analysis

Langer EMV-Technik manufactures high resolution IC measurement tools for IC analysis in the developmental stage. We would like to share information about a new product, which is being used to detect and guarantee IC safety and security.

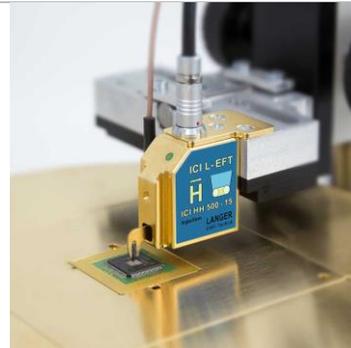
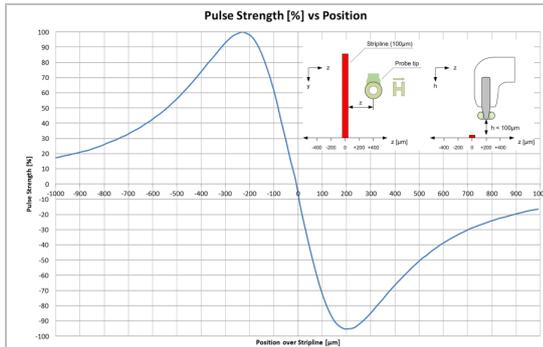
The ICI L-EFT set consists of up to a variety of ICI probes emitting electric or magnetic field or current pulses into an open die. This allows high precision and very high resolution IC analysis.

Side channel attacks can be simulated to test security-critical circuits. Special features include a very high resolution 500µm probe tip (allowing for the testing of extremely small areas) and a very low trigger to pulse jitter (allowing for the disruption of very specific points in the program sequence).



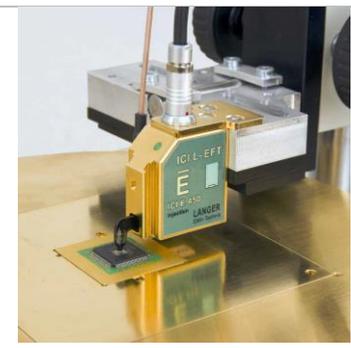
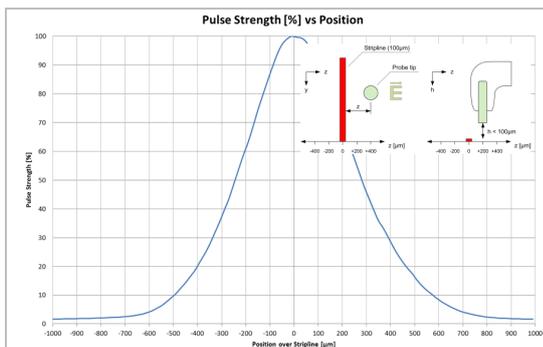
**ICI L-EFT Set: H-Feld Probe, E-Feld Probe, FBFI Probe**

The ICI HH500-15 L-EFT is a magnetic field source, generates fast transient pulses (< 2ns rise time). Pulse monitoring is realized via the measurement output of the magnetic source.



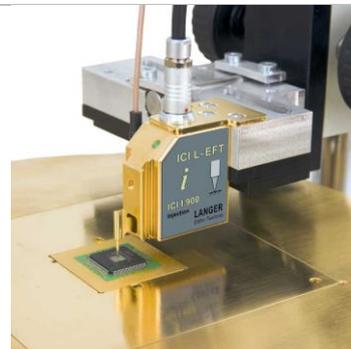
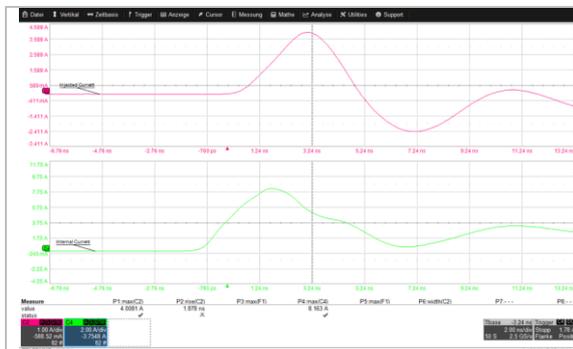
**Transvers scan pulse strength vs position ICI HH500-15 L-EFT**

The ICI E450 L-EFT is an E-field source with an electrode diameter of only 450 µm. With the very high resolution of the ICI E450 probe, it allows for individual areas in the IC to be selectively tested for electrical immunity.



**Transvers scan pulse strength vs position ICI E450 L-EFT**

The ICI I900 L-EFT is a current pulse source. The tip is spring-mounted and allows for testing of the substrate being contacted directly without damage to the sample. The ICI I900 can be used for FBBI and RBBI analysis of an open die.



**Pulse shape (maximum intensity) ICI E450 L-EFT**

All ICI probes are controlled via the provided BPS 202-Client software or DLL to match with your software needs.

Click here for further information: <https://www.langer-emv.com/en/category/ic-seitenkanalanalyse/94>

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